# Regions of Inversion



**Semiconductor Devices: Operation and Modeling Eq. 141** By: DR. M. Razaghi 141

# Regions of Inversion

#### **Approximate Limits**

For two terminal MOS onset of weak, moderate, and strong inversion by the surface potential values **TABLE 3.1** Approximate bounds between regions<sup>†</sup>





**Semiconductor Devices: Operation and Modeling By: DR. M. Razaghi** 142

Approximate Limits

Voltages corresponding to region of inversion is with some changes can be find as before, for example for moderate inversion voltage (neglecting exp term):

$$
V_{MB} = V_{FB} + (2\phi_F + \mathbf{V}_{CB}) + \gamma \sqrt{(2\phi_F + \mathbf{V}_{CB})}
$$

The corresponding values in terms of  $V_{GC}$  can be found by subtracting  $\bm{V_{CB}}$  , as suggested <u>before</u>. Thus, for example:

$$
V_M = V_{MB} - V_{CB} = V_{FB} + (2\phi_F) + \gamma \sqrt{(2\phi_F + V_{CB})}
$$

The fact that the quantities in Fig. increase with increasing  $\boldsymbol{V_{CB}}$  is a consequence of the body effect discussed before.

**As is apparent from the expressions in Table 3.1, how much**  $V_L$ **,**  $V_M$ **, and**  $V_H$ will increase for a given increase in  $\bm{V_{CB}}$  is determined by the value of the coefficient y; hence, the name body effect coefficient for this quantity.

$$
\gamma = \frac{\sqrt{2q\epsilon_s N_A}}{C'_{ox}}
$$

**The** *body effect* is **stronger** for heavier substrate dopings and/or thicker oxides.



<span id="page-2-0"></span>

	<b>Weak inversion</b>	<b>Moderate inversion</b>	<b>Strong inversion</b>
Definition in terms of surface potential $\psi_s$ (see Fig. $3.6a$ )	$\phi_F + V_{CB} \leq \psi_s$ $2\phi_F + V_{CB}$	$2\phi_F + V_{CB} \leq \psi_s$ $2\phi_F + V_{CB} + \phi_Z$	$2\phi_F + V_{CR} + \phi_Z \leq \psi_s$
Definition in terms of $V_{GB}$ for a given $V_{CB}$ (see Figs. 3.8b and 3.6)	$V_{LB} \leq V_{GB} < V_{MR}$	$V_{MB} \leq V_{GB} < V_{HB}$	$V_{HB} \leq V_{GB}$
Definition in terms of $V_{GC}$ for a given $V_{CB}$ (see Figs. $3.8b$ and $3.6$ )	$V_L \leq V_{GC} < V_M$	$V_M \leq V_{GC} < V_H$	$V_H \leq V_{GC}$
Definition in terms of $V_{CB}$ for a given $V_{GB}$ (see Fig. $3.1c$ and Sec. $3.5$ <sup>†</sup>	$V_U \geq V_{CB} > V_W$	$V_W \geq V_{CB} > V_O$	$V_O \geq V_{CB}$
$ Q_I' $ $ Q'_{B} $	$\ll 1$	Varies	$\gg$ 1 deep in strong inversion; not necessarily so near the bottom of the region
$\frac{C'_l}{C'_b}$	$\ll 1$ deep in weak inversion; not necessarily so near the top of the region	Varies	$\gg 1$
$d\psi_{s}$ $dV_{\!G\!B}$	Approximately constant; attains its maximum value in this region	Varies	Small
$d\psi_s$ $dV_{CB}$	Very small	Varies	Close to 1
Dependence of $Q'_l$ on $V_{GB}$ or $V_{GC}$ for $V_{CB}$ constant	Approximately exponential		Approximately first- degree polynomial
$d \ln  Q'_I $ $d\psi$	ф,	Varies	2ф.

**TABLE 3.2** Regions of inversion and properties (three-terminal MOS structure)

**Semiconductor Devices: Operation and Modeling By: DR. M. Razaghi** 144

# Strong Inversion

- In deep inversion :  $|Q'_I| \gg |Q'_B| \to C'_i \gg C'_b$
- As seen in Fig.,  $\psi_s$  changes only slightly with  $V_{GB}$  in strong inversion and can be assumed "pinned" to a fixed value.
- **This value for three terminal MOS increases by**  $V_{CB}$  **in compare to two terminal MOS**

$$
\psi_s \approx \phi_0 + V_{CB}
$$
  
\n
$$
\phi_0 \approx 2\phi_F + \Delta\phi
$$
  
\n
$$
\Delta\phi
$$
 is several  $\phi_T$ 

The depletion region width can then also be assumed pinned at a value  $d_{Bm}$ 

$$
d_{Bm} = \sqrt{\frac{2\epsilon_s}{qN_A}}\sqrt{\phi_0 + V_{CB}}
$$

Similarly, the depletion region charge is assumed to have reached a maximum value:

$$
Q'_B = -\sqrt{2q\epsilon_s N_A}\sqrt{\phi_0 + \mathbf{V_{CB}}} = -\gamma C'_{ox}\sqrt{\phi_0 + \mathbf{V_{CB}}}
$$





**Semiconductor Devices: Operation and Modeling Theory: By: DR. M. Razaghi** 145



Strong Inversion…

**For the case of strong inversion only,**  $V_{CB}$  **can be interpreted as the** *effective reverse bias* **of the field-induced junction** formed by the inversion layer and substrate.  $(d\psi_s/d{\bm V}_{{\bm C} {\bm B}} \approx 1)$ 

**The inversion layer charge can be obtained by:** 

$$
Q'_{I} = -C'_{ox}(V_{GB} - V_{FB} - \psi_{S}) - Q'_{B}
$$
  
\n
$$
Q'_{I} = -C'_{ox}(V_{GB} - V_{TB}) \text{ where } V_{TB} = V_{T} + V_{CB}
$$
  
\n
$$
V_{T} = \phi_{MS} - \frac{Q'_{0}}{C'_{ox}} + \phi_{0} - \frac{Q'_{B}}{C'_{ox}} = V_{FB} + \phi_{0} + \gamma \sqrt{\phi_{0} + V_{CB}}
$$

•The quantity  $V_{TB}$  is the G-B (gate-body) extrapolated threshold voltage. Its meaning is illustrated in Fig (d). It is not the border voltage for strong inversion mechanism!

Another way to express the equations using  $V_{GC}$ :

$$
\ddot{Q}'_I = -C'_{ox}(V_{GC} - V_T)
$$

The quantity  $V_T$  is the G-C extrapolated threshold voltage.

$$
V_T = V_{FB} + \phi_0 + \gamma \sqrt{\phi_0 + V_{CB}} = V_{T0} + (\gamma \sqrt{\phi_0 + V_{CB}} - \gamma \sqrt{\phi_0})
$$

The plot of  $V_T$  vs.  $V_{CB}$  has been included in [Fig](#page-2-0).





# Strong Inversion…

The threshold increase  $V_T - V_{T0}$  due to the body effect is shown vs.  $V_{CB}$  for various values of  $\gamma$  in Fig.

Note that, although we have assumed  $V_{CB} \geq 0$ , results are approximately valid even if  $V_{CB}$  is somewhat below zero (thus forward-biasing the source-body junction), as long as the  $\boldsymbol{V_{CB}}$  value is not enough to cause appreciable junction current. This has been confirmed experimentally.





**Semiconductor Devices: Operation and Modeling Theory: By: DR. M. Razaghi** 147

#### Weak Inversion

In weak inversion :  $|Q'_I| \ll |Q'_B| \to C'_i \ll C'_b$ 

In this case as the  $\psi_s < 2\phi_F + V_{CB}$ , like before we can find:  $Q'_I =$  $-\sqrt{2q\epsilon_s}N_A$  $2\sqrt{\psi_s}$  $\phi_T e^{(\psi_s-(2\phi_F+\bm{V_{CB}}))/\phi_T}$ 

In weak inversion,  $V_{CB}$  cannot be interpreted as an effective reverse bias, as explained before.

In weak inversion, the surface potential is practically independent of  $V_{CB}$  and is practically equal to  $\psi_{sa}$ 

$$
\psi_s \approx \psi_{sa}(V_{GB}) = \left(-\frac{\gamma}{2} + \sqrt{\frac{\gamma^2}{4} + V_{GB} - V_{FB}}\right)
$$

Therefore, in mentioned Eq. the *only* term dependent on  $\bm{V_{CB}}$  is  $e^{-(\bm{V_{CB}})/\phi_T}$ 

$$
Q'_{I} = \frac{-\sqrt{2q\epsilon_{s}N_{A}}}{2\sqrt{\psi_{sa}(V_{GB})}}\phi_{T}e^{(\psi_{sa}(V_{GB})-2\phi_{F})/\phi_{T}}e^{-(V_{CB})/\phi_{T}}
$$





**Semiconductor Devices: Operation and Modeling The By: DR. M. Razaghi 148** 148

### Weak Inversion…

For a fixed  $V_{CB}$ ,  $Q'_I$  turns out to be nearly exponentially dependent on  $V_{GB}$ .

**Let**  $V_{CB}'$  **denote the constant value of**  $V_{CB}$  **for which** this curve is obtained.

As seen, the width of the region in terms of  $\psi_{sa}$  is only  $_{2\phi_F+V_{CB}}$  $\phi_F$ .

As  $V_{GB}$  changes over the region, the corresponding variation of the term  $\sqrt{\psi_{sa}(V_{GB})}$ , is very small compared with the large variation of the exponential in that equation. Therefore:

$$
\sqrt{\psi_{sa}(V_{GB})} \approx \sqrt{2\phi_F + V'_{CB}}
$$





**Semiconductor Devices: Operation and Modeling Theory: By: DR. M. Razaghi** 149 149

#### Weak Inversion…

**-Thus:** 

$$
Q'_{I} = \frac{-\sqrt{2q\epsilon_{s}N_{A}}}{2\sqrt{2\phi_{F} + V'_{CB}}} \phi_{T}e^{(\psi_{Sa} - 2\phi_{F})/\phi_{T}}e^{-(V'_{CB})/\phi_{T}}
$$

In analogy with the corresponding development for the two-terminal structure, a simplified, approximate expression can be developed based on the  $\,$ observation that the slope of  $\psi_{sa}(V_{GB})$  is nearly constant in weak inversion.

hat the *inverse* of this slope was denoted by *n*

$$
n = \left(\frac{d\psi_{sa}}{dV_{GB}}\right)^{-1} = 1 + \frac{\gamma}{2\sqrt{\psi_{sa}(V_{GB})}}
$$

$$
n = n\Big|_{\psi_{sa} = 2\phi_F + V'_{GB}} = 1 + \frac{\gamma}{2\sqrt{2\phi_F + V'_{CB}}}
$$

Then:

$$
\boxed{\color{red} \textbf{U}}
$$

$$
\psi_{sa} - (2\phi_F + V_{CB}') \approx \frac{1}{n}(V_{GB} - V_{MB}) = \frac{1}{n}(V_{GC} - V_M)
$$





**Semiconductor Devices: Operation and Modeling Theory: By: DR. M. Razaghi** 150

#### Weak Inversion…

Substituting to previous equations:

 $Q'_I \approx Q'_M e^{(V_{GB}-V_{MB})/n\phi_T}$ 

*or*

$$
Q'_I \approx Q'_M e^{(V_{GC}-V_M)/n\phi_T}
$$

Where

$$
Q'_M = \frac{-\sqrt{2q\epsilon_s}N_A}{2\sqrt{2\phi_F + V'_{CB}}} \phi_T
$$

This result represents the value of  $Q'_I$  at the top of weak inversion ( $V_{GB} = V_{MB}$ ).

**• These equations predicts exponential behavior for**  $Q'_I$  **in weak inversion.** 

As was the case with the two-terminal structure, this is only approximately true.

- **If V<sub>GB</sub>** is fixed and V<sub>CB</sub> is varied instead above equations can be misleading. The reason is that the dependence of  $Q'_I$ on  $\bm{V_{CB}}$  is hidden in  $Q_M^r$ ,  $V_{MB}$  and *n*, each of which depends on  $\bm{V_{CB}}$  in a complicated manner.
- In this case previous Eq. is ideal for such cases, since it makes explicit the exponential dependence of  $Q'_I$  on  $V_{CB}$  in a simple manner.





### Moderate Inversion

For a given  $\boldsymbol{V}_{GB}$  value in moderate inversion, one can numerically solve the *implicit equation* for  $\psi_s$  and substitute  $\psi_s$  into equation to find  $Q'_I$ .



**Semiconductor Devices: Operation and Modeling By: DR. M. Razaghi** 152

